

**Search Notes**

Application/Control No.

10/758,983

Examiner

Patricia T. Nguyen

Applicant(s)/Patent under  
Reexamination

YAMAKAWA ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
333	202	10/15/2005	PN
	206		
	207		
	219.1		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
333	202	10/15/2005	PN
	206		
	207		
333/219.1			

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST		